Notice of References Cited

Application/Control No.

10/042,185

Examiner

TAN X. DINH

Applicant(s)/Patent Under Reexamination DENO ET AL.

Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	А	US-6,687,214 B2	02-2004	Kato et al.	369/275.4
*	В	US-6,599,607 B1	07-2003	Takishita et al.	369/275.4
*	С	US-6,590,857 B2	07-2003	Ohkubo et al.	369/275.4
*	D	US-6,504,815 B1	01-2003	Fujii et al.	369/275.4
*	E	US-6,490,240 B1	12-2002	Usami, Yoshihisa	369/275.4
*	F	US-6,404,729 B1	06-2002	Yamaoka et al.	369/275.4
*	G	US-5,604,726 A	02-1997	Karube, Hiroo	369/275.4
*	Н	US-6,679,430 B2	01-2004	Kato et al.	369/275.4
*	i	US-6,704,274 B2	03-2004	Takahata et al.	369/275.4
*	J	US-6,673,411 B2	01-2004	Koide et al.	369/275.4
*	К	US-6,493,312 B1	12-2002	Negishi et al.	369/275.4
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				·	
	0				·	
	Р					
	Q					
	R				·	
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W	,				
	X	(Co. MOED C. 707.05(a)				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.